

RNG4_ES Public Use Document

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Table of Contents

1 Description 3
2 Security Boundary 4
3 Operating Conditions 5
4 Configuration Settings 5
5 Physical Security Mechanisms 6
6 Conceptual Interfaces 6
7 Min-Entropy Rate 6
8 Health Tests 7
9 Maintenance 7
10 Required Testing 7

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1 Description

This document describes the design of the NXP RNG4_ES. The entropy source (depicted in Figure 1) is composed of a few major sections: the noise source and entropy estimator (health tests). This design uses either one ring oscillator as the Up Oscillator (in which case the system clock is used as the Down Oscillator) or two ring oscillators (in which case a rising edge of the Down Oscillator triggers the decrementing of the Down Counter). The general design of the ring oscillators consists of an inverting enabling gate and an even number of additional inverting delay elements formed into a ring. There are two ring oscillators within all of the MCX N Series MCU designs covered by this Public Use Document.

This assessment was conducted using data and parameters measured in the evaluated version described In Table 1.

Table 1: Evaluated Entropy Source Specification

Identifier	Details
Entropy Source Name	RNG4_ES
Part Numbers	MCX N94x/54x/23x
Hardware Revision	MCX N94x/54x A1 MCX N23x A0
Entropy Category	Physical (P)
Test Platform(s)	MCX N94x/54x/23x
Entropy Estimation Track (per SP 800-90B §3.1.2)	Non-IID

When used to seed an SP 800-90A DRBG, the seeding requirements listed in the table below must be met.

DRBG Security Strength	Bits Required to Instantiate (Random Nonce)	Bits Required to Instantiate (Nonce Provided)
128-bit	232	155
192-bit	348	232
256-bit	464	309

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2 Security Boundary

The RNG4_ES noise source is depicted in block diagram below. The entire entropy source is implemented in hardware.

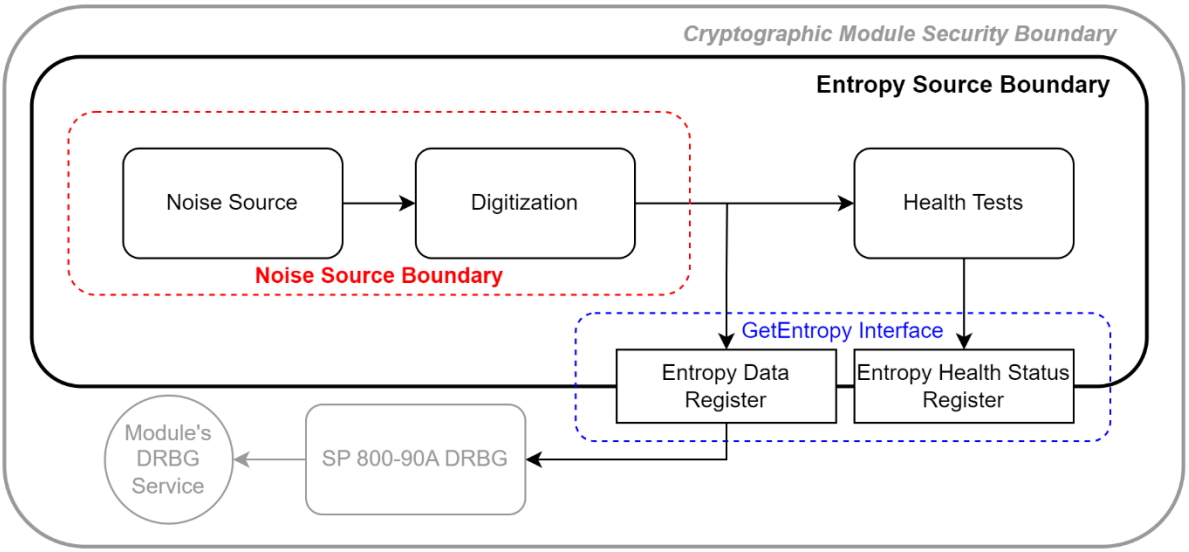


Figure 1: RNG4 entropy source

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3 Operating Conditions

The Entropy-relevant operating conditions are given in Table 2.

Table 2: Entropy-Relevant Operating Conditions

Parameter	Value
Temperature	-40C to 125C
Voltage	0.9V to 1.26V

4 Configuration Settings

All entropy-relevant parameters must be verified as set as specified in Table 3.

Table 3: Entropy-Relevant Configuration Parameters

Parameter	Value	Description
Entropy Delay	25000	Ring oscillator cycle count corresponding to a single bit of entropy per the [EAR].
von Neumann Post Processing	Disabled	Enable or disable Von Neumann post-processing.
Health Test Bounds	As described in Table 4	See Table 4
Health Test Retries Allowed	1	Number of attempts to retry health testing.
Ring Oscillator Clock Divider	0	A provision to slow the ring oscillator rate; unused.
Downclock Source	Dual Osc.	Sample clock source selector.
Statistical Test Block Size	1024	Number of bits generated and tested by the self-tests.

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5 Physical Security Mechanisms

The RNG4_ES entropy source operates within the physical protections of the associated SoC package, a commercial plastic ball grid array package. In addition, the NXP SoC devices are mounted onto PCBs, protecting access to the ball grid array.

6 Conceptual Interfaces

The RNG4_ES provides entropy data to the cryptographic module in which it is implemented, and this module is considered to be the user of the entropy source. The process of using the GetEntropy() interface is the process of reading the Entropy Data Register, and this interface is only provided to the user of the entropy source.

7 Min-Entropy Rate

The min-entropy rate of the output of the RNG4_ES is 0.809214 bits/bit.

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8 Health Tests

The RNG4_ES implements the health tests with NXP recommended bounds as follows:

Table 4. Health Tests and NXP Recommended Bounds

Health Test	1024-bit Block	
	Min	Max
Monobit Test	427	596
Run Length 1	75	187
Run Length 2	28	105
Run Length 3	33	97
Long Runs		32

If a generated block of entropy data fails the self-test, the design can be configured to discard the data and generate a new block of data to be tested. A re-try counter (see the *Health Test Retries Allowed* configuration parameter) is used to specify how many times data should be discarded before signaling an error.

9 Maintenance

The RNG4_ES design does not require maintenance.

10 Required Testing

The RNG4_ES as incorporated in the MCX N Series MCU family was tested by collected data from the device operating in its designated operational range and processed with the SP 800-90B tool. Test data was collected following the requirements of Section 3 of SP 800-90B. No additional testing is required by the end user.

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